Half Bridge Gate Driver(Isolated High & Non-Isolated Low)

NCV57200

The NCV57200 is a high voltage gate driver with one non-isolated low side gate driver and one galvanic isolated high or low side gate driver. It can directly drive two IGBTs in a half bridge configuration. Isolated high side driver can be powered with an isolated power supply or with Bootstrap technique from the low side power supply.

The galvanic isolation for the high side gate driver guarantees reliable switching in high power applications for IGBTs that operate up to 800 V, at high dv/dt. The optimized output stages provide a mean of reducing IGBT losses. Its features include two independent inputs with deadtime and interlock, accurate asymmetric UVLOs, and short and matched propagation delays. The NCV57200 operates with its V_{CC}/V_{B} up to 20 V.

Features

- High Peak Current Output (+1.9 A / -2.3 A)
- Low Output Voltage Drop for Enhanced IGBT Conduction
- Secured Output Low State without V_{DD/}V_B
- Floating Channel for Bootstrap Operation up to +800 V
- CMTI up to 50 kV / us
- Reliable Operation for V_S Negative Swing to -800 V
- VDD & VBS Supply Range up to 20 V
- 3.3 V, 5 V, and 15 V Logic Input
- Asymmetric Under Voltage Lockout Thresholds for High Side and Low Side
- Matched Propagation Delay 90 ns
- Built-in 20 ns Minimum Pulse Width Filter (or Input Noise Filter)
- Built-in 340 ns Dead-Time and High and Low Inputs Interlock
- Output in Phase with Input Signal
- AEC-Q100 Qualified and PPAP Capable
- This Device is Pb–Free, Halogen Free/BFR Free and is RoHS Compliant

Typical Applications

- OBC
- PTC Heater
- e-Compressors
- Automotive Power Supplies



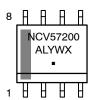
ON Semiconductor®

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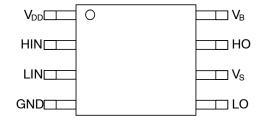
SOIC-8 NB CASE 751-07

MARKING DIAGRAM



NCV57200 = Specific Device Code
A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week
■ Pb-Free Package

PIN CONNECTIONS



ORDERING INFORMATION

See detailed ordering and shipping information on page 8 of this data sheet.

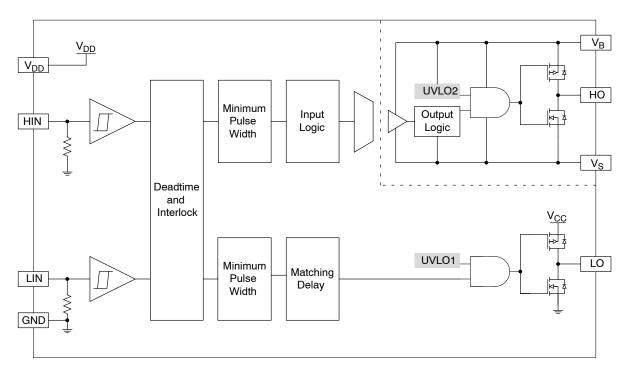


Figure 1. Simplified Block Diagram

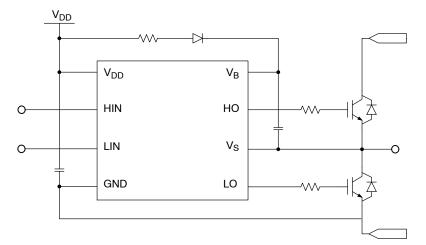


Figure 2. Simplified Application Schematics

Table 1. FUNCTION DESCRIPTION

Pin Name	No.	I/O	Description
V_{DD}	1	Power	Low side and main power supply. A good quality bypassing capacitor is required from this pin to GND and should be placed close to the pins for best results. The under voltage lockout (UVLO) circuit enables the device to operate at power
			on when a typical supply voltage higher than $V_{UVLO1-OUT-ON}$ is present. Please see Figure 5 for more details. A filter time of typical 1.5 μ s helps to suppress noise on V_{DD} pin.
HIN	2	ı	High side non-inverting gate driver input. It has an equivalent pull–down resistor of 125 k Ω to ensure that output is low in the absence of an input signal. A minimum positive or negative going pulse width is required at HIN before HO reacts.
			It adopts 3.3 V logic signal thresholds for input voltage up to V_{DD} . There is deadtime and interlocking logic between HIN and LIN.
LIN	3	ı	Low side non-inverting gate driver input. It has an equivalent pull–down resistor of 125 k Ω to ensure that output is low in the absence of an input signal. A minimum positive or negative going pulse width is required at LIN before LO reacts.
			It adopts 3.3 V logic signal thresholds for input voltage up to V_{DD} . There is deadtime and interlocking logic between HIN and LIN.
GND	4	Power	Logic ground and low side driver return.
LO	5	0	Low side driver output that provides the appropriate drive voltage and source/ sink current to the IGBT gate. LO is actively pulled low during startup and under UVLO1 condition. There is deadtime and interlocking logic to prevent unintended HO and LO cross conduction.
V _S	6	Power	Bootstrap return or high side floating supply offset.
НО	7	0	Galvanic isolated high side driver output that provides the appropriate drive voltage and source/sink current to the IGBT gate. HO is actively pulled low during startup and under UVLO2 condition. There is deadtime and interlocking logic to prevent unintended HO and LO cross conduction.
V _B	8	Power	Bootstrap or high side floating power supply. A good quality bypassing capacitor is required from this pin to $V_{\rm S}$ and should be placed close to the pins for best results.
			The under voltage lockout (UVLO) circuit enables the device to operate at power on when a typical supply voltage higher than V _{UVLO2-OUT-ON} is present. Please see Figure 5 for more details. A filter time of typical 1.5 μs helps to suppress noise on V _B pin.

Table 2. ABSOLUTE MAXIMUM RATINGS (Note 1) Over operating free-air temperature range unless otherwise noted

Symbol	Minimum	Maximum	Unit
V _S	-900	900	V
	-900	900	
V _B	-900	900	V
	-900	900	
V _{DD}	-0.3	25	V
V _{BS}	-0.3	25	V
V _{HO}	V _S -0.3	V _B +0.3	V
V_{LO}	-0.3	V _{DD} +0.3	V
V _{IN}	-0.3	V _{DD} +0.3	V
dV _S /dt		±50	V/ns
TJ(max)	-40	150	°C
TSTG	-65	150	°C
ESDHBM		±4	kV
ESDCDM		±2	kV
MSL		1	-
TSLD		260	°C
	V _S V _B V _{DD} V _{BS} V _{HO} V _{LO} V _{IN} dV _S /dt TJ(max) TSTG ESDHBM ESDCDM MSL	V _S -900 -900 -900 -900 -900 -900 -900 -900	V _S -900 900 -900 900 V _B -900 900 -900 900 V _{DD} -0.3 25 V _{BS} -0.3 25 V _{HO} V _S -0.3 V _B +0.3 V _{LO} -0.3 V _{DD} +0.3 V _{IN} -0.3 V _{DD} +0.3 dV _S /dt ±50 TJ(max) -40 150 ESDHBM ±4 ESDCDM ±2 MSL 1

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.

- 2. This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per AEC-Q100-002 (EIA/JESD22-A114).

 - ESD Charged Device Model tested per AEC-Q100-011 (EIA/JESD22-C101).
 - Latchup Current Maximum Rating: ≤ 100 mA per JEDEC standard: JESD78, 125°C.
- 3. For information, please refer to our Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

Table 3. THERMAL CHARACTERISTICS

Parameter	Symbol	Value	Unit	
Thermal Characteristics, SOIC–8 (Note 4) Thermal Resistance, Junction–to–Air (Note 5)	ReJA	167	°C/W	

- 4. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.
- 5. Values based on copper area of 100 mm² (or 0.16 in²) of 1 oz copper thickness and FR4 PCB substrate.

Table 4. RECOMMENDED OPERATING RANGES (Note 6)

Parameter	Symbol	Min	Max	Unit
High-Side Supply Voltage	V _B	V _S +UVLO2	V _S +20	V
High-Side Supply Offset Voltage	V _S	-800	800	V
High-Side (HO) Output Voltage	V _{HO}	V _S	V _B	V
Low-Side (LO) Output Voltage	V_{LO}	GND	V_{DD}	V
Logic Input Voltage (HIN, LIN)	V _{IN}	GND	V_{DD}	V
Low-Side Supply Voltage	V _{DD}	UVLO1	20	V
Ambient Temperature	T _A	-40	+125	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

6. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.

 $\begin{tabular}{ll} \textbf{Table 5. ELECTRICAL CHARACTERISTICS}$ $V_{DD} = V_{BS} = 15$ V. \\ For typical values $T_A = 25^{\circ}$C, for min/max values, T_A is the operating ambient temperature range that applies, unless otherwise noted. \\ \end{tabular}$

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
VOLTAGE SUPPLY						
V _{BS} Supply Under Voltage Output Enabled		V _{UVLO2} OUT	11	11.5	12	V
V _{BS} Supply Under Voltage Output Disabled		V _{UVLO2} -OUT -OFF	10	10.5	11	V
V _{BS} Supply Voltage Output Enabled/Disabled Hysteresis		V _{UVLO2-HYST}		1.0		V
V _{DD} Supply Under Voltage Output Enabled		V _{UVLO1} OUT	12	12.5	13	V
V _{DD} Supply Under Voltage Output Disabled		V _{UVLO1-OUT}	11	11.5	12	V
V _{DD} Supply Voltage Output Enabled/Disabled Hysteresis		V _{UVLO1-HYST}		1.0		V
Leakage Current Between V_{S} and GND	$V_S = \pm 800 \text{ V}, T_A = 25^{\circ}\text{C}$ $V_S = \pm 800 \text{ V}, T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	I _{HV_LEAK1}		20	200 600	nA
Quiescent Current V _{BS} Supply (V _B Only)	HO = Low	I _{QBS1}		260	325	μΑ
Quiescent Current V _{BS} Supply (V _B Only)	HO = High	I _{QBS2}		330	440	μΑ
Quiescent Current V_{DD} Supply (V _{DD} Only)	V _{LIN} = Float, V _{HIN} = 0 V,	I _{QDD1}		380	440	μΑ
Quiescent Current $V_{\rm DD}$ Supply (V _{DD} Only)	V _{LIN} = 3.3 V, V _{HIN} = 0 V,	I _{QDD2}		440	500	μΑ
Quiescent Current V _{DD} Supply (V _{DD} Only)	V _{LIN} = 0 V, V _{HIN} = 3.3 V,	I _{QDD3}		2.4	3	mA
LOGIC INPUT		•		•	•	
Low Level Input Voltage		V _{IL}			0.9	V
High Level Input Voltage		V _{IH}	2.4			V
Logic "1" Input Bias Current	V _{LIN} = 3.3 V, V _{HIN} = 3.3 V	I _{LIN1+} , I _{HIN1+}		25	50	μΑ
Logic "1" Input Bias Current	V _{LIN} = 20 V, V _{HIN} = 20 V, V _{DD} = V _{BS} = 20 V	ILIN2+, IHIN2+		100	150	μΑ
Logic "0" Input Bias Current	V _{LIN} = 0 V, V _{HIN} = 0 V	I _{LIN} -, I _{HIN} -		40	100	nA
DRIVER OUTPUT						
Output Low State	I _{SINK} = 200 mA, T _A = 25°C	V _{OL1}		0.2	0.3	V
	I _{SINK} = 200 mA, T _A = -40°C to 125°C	V _{OL2}			0.5	
Output High State	I _{SRC} = 200 mA, T _A = 25°C	V _{OH1}	14.4	14.5		V
	I _{SRC} = 200 mA, T _A = -40°C to 125°C	V _{OH2}	14			
Peak Driver Current, Sink	V _{HO} = V _{LO} = 15 V	I _{PK-SNK1}		2.3		Α
(Note 7)	V _{HO} = V _{LO} = 9 V (near Miller Plateau)	I _{PK-SNK2}		2.1		
Peak Driver Current, Source	V _{HO} = V _{LO} = 0 V	I _{PK-SRC1}		1.9		Α
(Note 7)	V _{HO} = V _{LO} = 9 V (near Miller Plateau)	I _{PK} -SRC2		1.5		

Table 5. ELECTRICAL CHARACTERISTICS V_{DD} = V_{BS} = 15 $V_{\rm c}$

For typical values $T_A = 25^{\circ}C$, for min/max values, T_A is the operating ambient temperature range that applies, unless otherwise noted.

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit	
IGBT SHORT CIRCUIT CLAMPING							
Clamping Voltage (V _{HO} – V _B) / (V _{LO} – V _{DD})	I_{HO} = 100 mA, I_{LO} = 100 mA (pulse test, t_{CLPmax} = 10 μ s)	V _{CLAMP} -OUT		0.8	1.3	V	
DYNAMIC CHARACTERISTIC		-					
HO High Propagation Delay	C _{LOAD} = 1 nF, V _{IH} to 10% of Output Change for PW > 150 ns	t _{PD-ON-H}	60	90	110	ns	
HO Low Propagation Delay	C _{LOAD} = 1 nF, V _{IL} to 90% of Output Change for PW > 150 ns	t _{PD-OFF-H}	60	90	110	ns	
Propagation Delay Distortion(HS) (= t _{PD-ON} - t _{PD-OFF})	PW >150 ns	t _{DISTORT-H}	-25	0	25	ns	
LO High Propagation Delay	CLOAD = 1 nF, VIH to 10% of Output Change for PW > 150 ns	t _{PD-ON-L}	60	90	110	ns	
LO Low Propagation Delay	CLOAD = 1 nF, VILto 90% of Output Change for PW > 150 ns	t _{PD-OFF-L}	60	90	110	ns	
Propagation Delay Distortion(LS) (= t _{PD-ON} - t _{PD-OFF})	PW >150 ns	^t DISTORT-L	-25	0	25	ns	
High Prop Delay Distortion between High and Low Sides	PW > 150 ns	t _{DISTORT-HLH}	-25	0	25	ns	
Low Prop Delay Distortion between High and Low Sides	PW > 150 ns	t _{DISTORT-HLL}	-25	0	25	ns	
Rise Time(HS) (see timing diagram)	C _{LOAD} = 1 nF, 10% to 90% of Output Change	t _{RISE-H}		13		ns	
Fall Time(HS) (see timing diagram)	C _{LOAD} = 1 nF, 90% to 10% of Output Change	t _{FALL-H}		8		ns	
Rise Time(LS) (see timing diagram)	C _{LOAD} = 1 nF, 10% to 90% of Output Change	t _{RISE-L}		13		ns	
Fall Time(LS) (see timing diagram)	C _{LOAD} = 1 nF, 90% to 10% of Output Change	t _{FALL-L}		8		ns	
Deadtime, HO Delays	V _{LIN/HIN} = 0 V and 3.3 V	t _{DT1}		340		ns	
Deadtime, LO Delays	V _{LIN/HIN} = 0 V and 3.3 V	t _{DT2}		350		ns	
Deadtime Matching		t _{MDT}		10		ns	
Minimum Pulse Width Filtering Time	T _A = 25°C	t _{MIN1} , t _{MIN2}	10		40	ns	
UVLO Fall Delay (HO and LO)		t _{UV1}		1300		ns	
UVLO Rise Delay (HO and LO)		t _{UV2}		1100		ns	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

7. Values based on design and/or characterization.

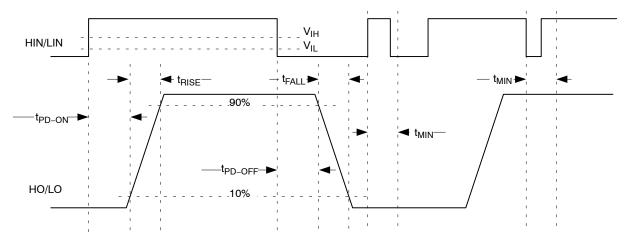


Figure 3. Propagation Delay, Rise and Fall Time

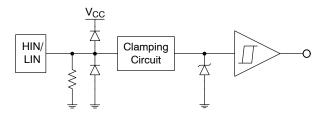


Figure 4. Input Pin Structure

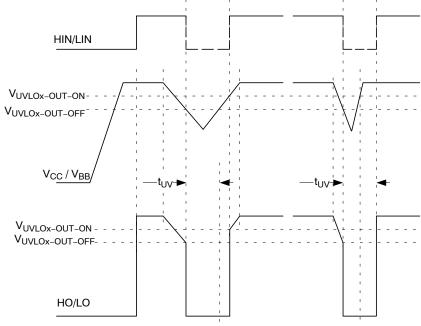


Figure 5. UVLO

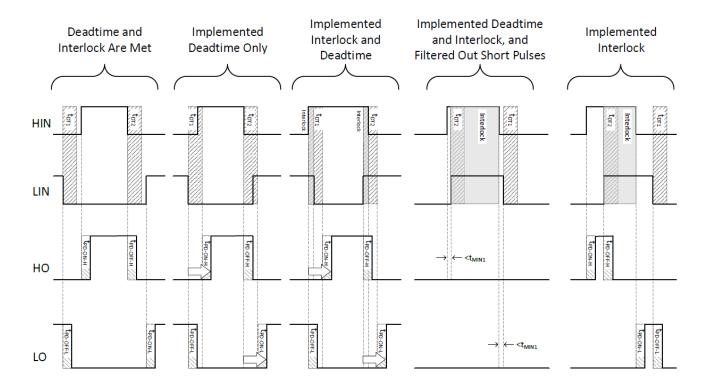


Figure 6. Deadtime, Interlock and Output Minimum Pulse Width

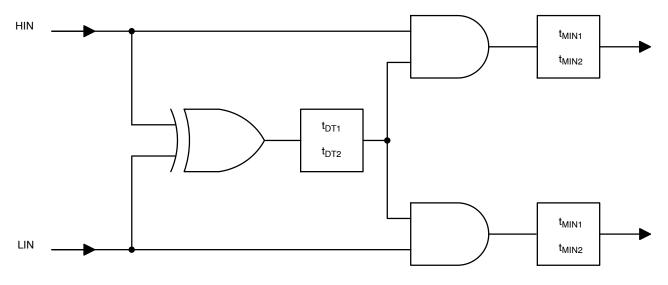


Figure 7. Input Circuit

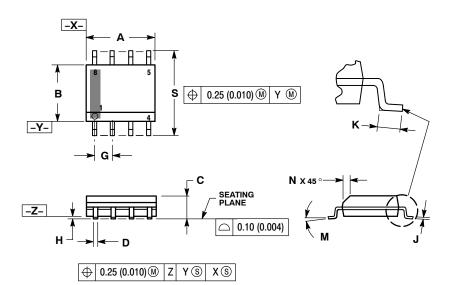
ORDERING INFORMATION

Device	Package	Shipping [†]	
NCV57200DR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel	

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

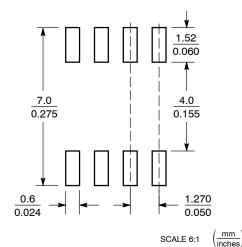
SOIC-8 NB CASE 751-07 **ISSUE AK**



- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006)
- PER SIDE.
 DIMENSION D DOES NOT INCLUDE DAMBAR DIMENSION DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751–07.

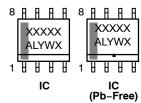
	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27	1.27 BSC		0 BSC	
Н	0.10	0.25	0.004	0.010	
7	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

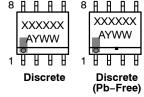
GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location Α

= Wafer Lot = Year = Work Week W

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

WW = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "=", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 1: PIN 1. EMITTER 2. COLLECTOR 3. COLLECTOR 4. EMITTER 5. EMITTER 6. BASE 7. BASE 8. EMITTER	STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 5. BASE, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1	STYLE 4: PIN 1. ANODE 2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE
STYLE 5: PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. DRAIN 5. GATE 6. GATE 7. SOURCE 8. SOURCE	STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE	STYLE 7: PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd	STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1
STYLE 9: PIN 1. EMITTER, COMMON 2. COLLECTOR, DIE #1 3. COLLECTOR, DIE #2 4. EMITTER, COMMON 5. EMITTER, COMMON 6. BASE, DIE #2 7. BASE, DIE #1 8. EMITTER, COMMON	STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. BIAS 2 7. INPUT 8. GROUND	STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 13: PIN 1. N.C. 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN	STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 17: PIN 1. VCC 2. V2OUT 3. V1OUT 4. TXE 5. RXE 6. VEE 7. GND 8. ACC	STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 21: PIN 1. CATHODE 1 2. CATHODE 2 3. CATHODE 3 4. CATHODE 4 5. CATHODE 5 6. COMMON ANODE 7. COMMON ANODE 8. CATHODE 6	STYLE 22: PIN 1.	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	STYLE 24: PIN 1. BASE 2. EMITTER 3. COLLECTOR/ANODE 4. COLLECTOR/ANODE 5. CATHODE 6. CATHODE 7. COLLECTOR/ANODE 8. COLLECTOR/ANODE
STYLE 25: PIN 1. VIN 2. N/C 3. REXT 4. GND 5. IOUT 6. IOUT 7. IOUT 8. IOUT	STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 29: PIN 1. BASE, DIE #1 2. EMITTER, #1 3. BASE, #2 4. EMITTER, #2 5. COLLECTOR, #2 6. COLLECTOR, #2 7. COLLECTOR, #1 8. COLLECTOR, #1	STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		

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